

# High-Performance p-Type Transparent Conducting CuI–Cu<sub>2</sub>O Thin Films with Enhanced Hole Mobility, Surface, and Stability

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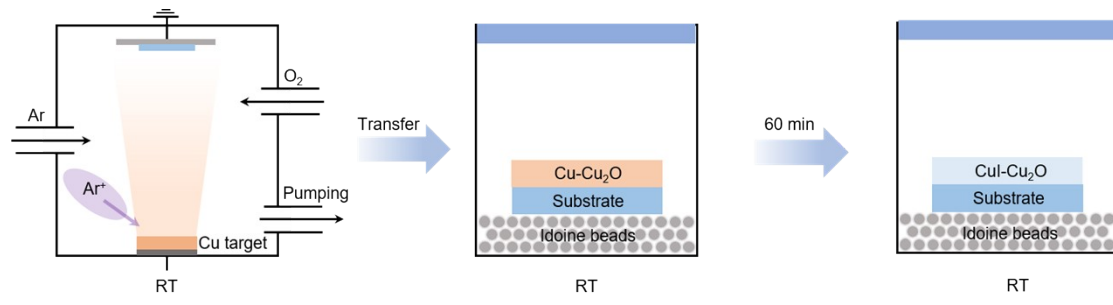
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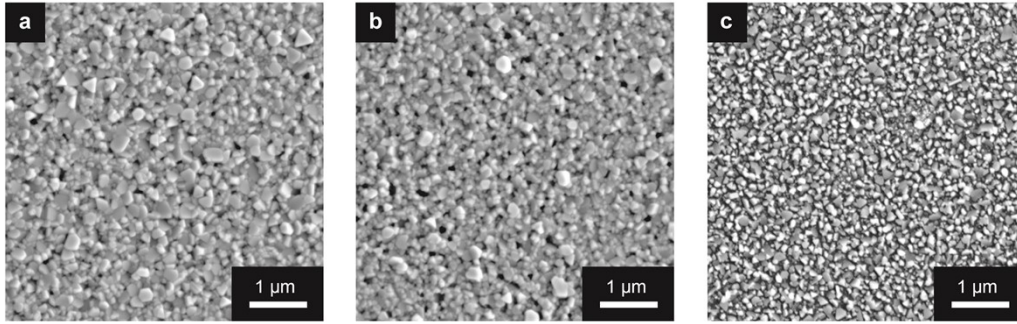
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**Figure S1.** Schematic diagram of the CuI-Cu<sub>2</sub>O films deposition process.



**Figure S2.** SEM images of the CuI–Cu<sub>2</sub>O films after ageing for 6 months under ambient condition with O<sub>2</sub> flow rate of (a) 0 sccm, (b) 0.10 sccm and (c) 0.20 sccm.